

Notice of References Cited	Application/Control No. 08/811,742	Applicant(s)/Patent Under Reexamination ZHANG ET AL.	
	Examiner Khiem D Nguyen	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-140915	05-1990	Japan	Hideaki Oka	H01L 21/20
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	A.Y. Kuznetsov et al. Microsc. Semicond. Mater. Conf. '93 Proc. in inst. Phys. Conf. 134(4)(1993)191. "Silicide precipitate formation and solid phase regrowth of Ni+ implanted a-Si"
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.